

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/938,328	SCOTTO ET AL.	
Examiner	Art Unit	
Tan Dean D. Nguyen	3629	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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